

Multimodal Modeling of DPC-STEM To Improve Electrostatic Sensitivity

Austin Gerlt^{1,2} Edwin Supple² and Alexana Roshko²

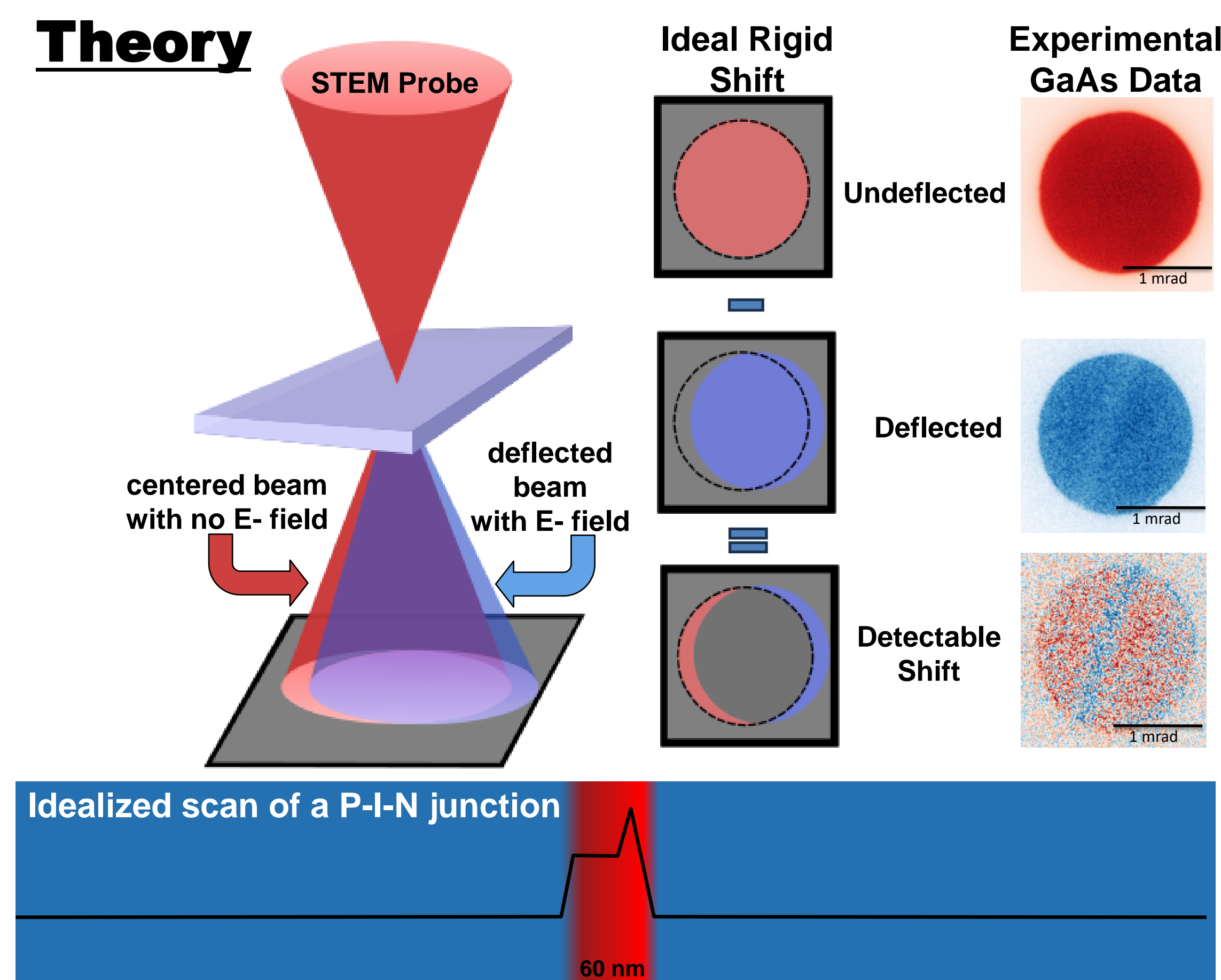
¹Southeastern Universities Research Association, New York, NY, United States

²Quantitative Nanostructure Characterization Group, NIST, Boulder, CO, United States

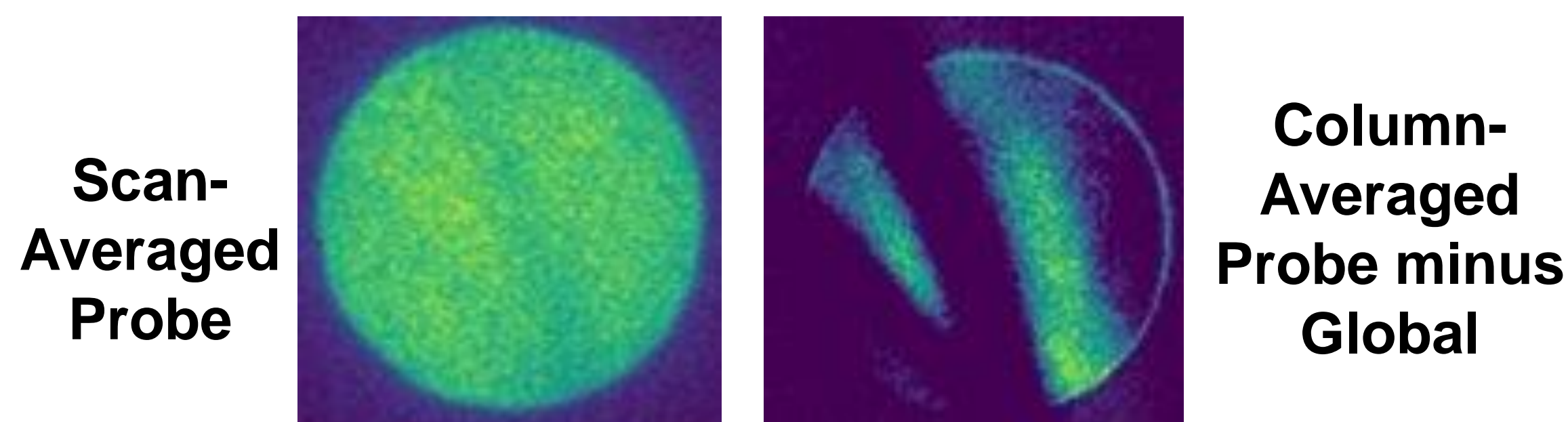
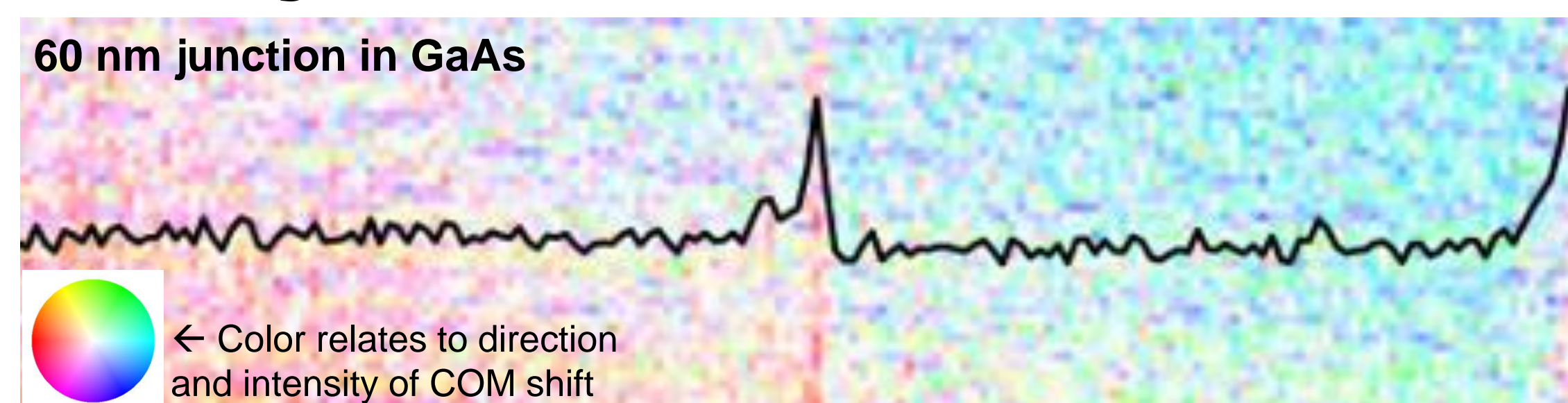
BACKGROUND

Differential Phase Contrast Scanning Transmission Electron Microscopy (DPC-STEM) is a method by which electrostatic forces can be spatially resolved around atomic-scale defects and junctions.

Theory

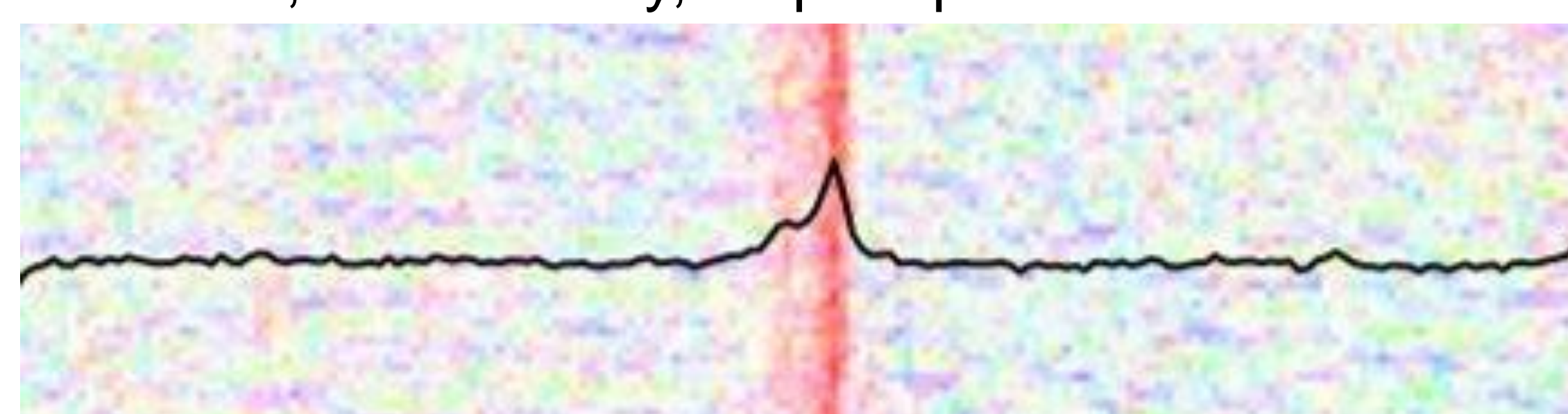


Reality



Inherent diffraction events like Kikuchi and HOLZ lines affect the probe, altering the **Center-of-Mass** (COM) calculation and obscuring the electric field data.

This can, with difficulty, be post-processed out ...

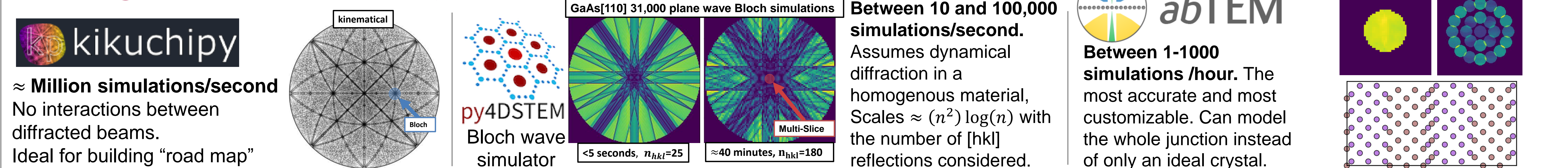


Motivation: What if instead, the diffraction events could be modeled *a-priori* and thus avoided altogether?

GOAL

Can we quickly predict which specimen orientations will minimize diffraction interference for DPC-STEM?

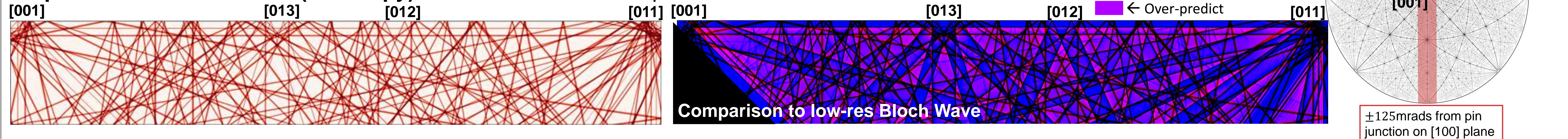
Modeling options: Kinematical, Bloch Wave, and Multi-Slice



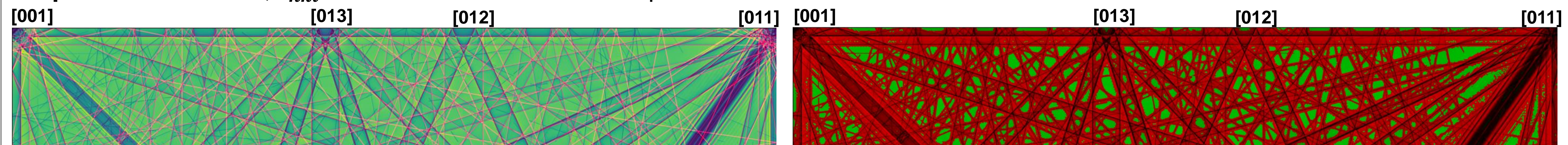
Sequential Search models of increasing fidelity

- At a 100 μ -rad mesh, ≈ 1 billion unique probes. Symmetry and experimental constraints reduces this to ≈ 9.8 million.
- This is still too many to fully model, but many options can be eliminated by fast, lower-fidelity checks.

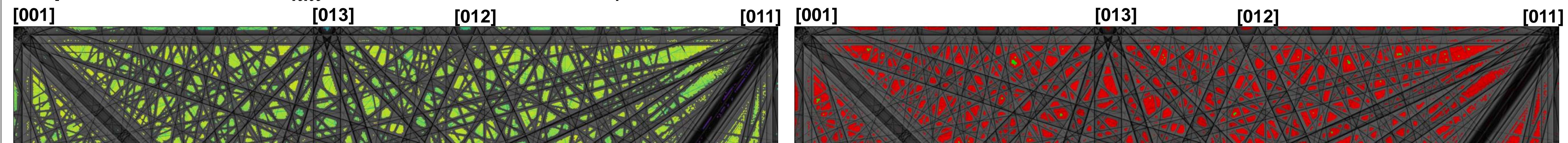
Step 1: Kinematical Guides (kikuchipy): Reduce to 7.8 million options in ≈ 2 seconds



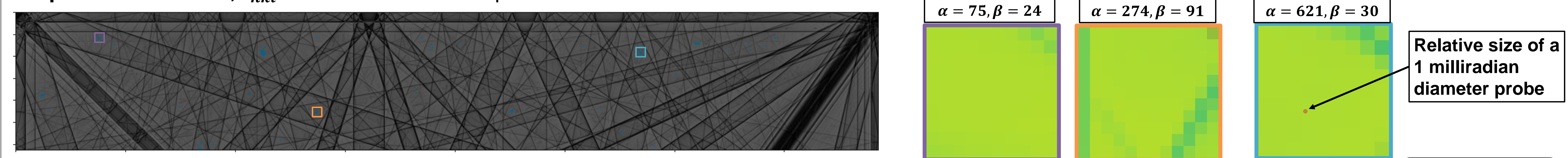
Step 2a: Bloch Wave, $n_{hkl} = 20$: Reduce to 1.6 million options in ≈ 3 minutes



Step 2b: Bloch Wave, $n_{hkl} = 50$: Reduce to 12,944 options ≈ 3 minutes



Step 2c: Bloch Wave, $n_{hkl} = 180$: Reduce to 15 options in ≈ 3 minutes



Next Steps

- **Computational verification via Multi-Slice**
 - Ab-TEM is capable of capturing crucial additional physics (lattice strain at the junction, thermal effects, lens aberrations, etc), and is an ideal final verification step.
- **Experimental verification**
 - Scheduled for mid-August 2025
- **Additional modeling for a radially processed probe**
 - Akin to searching a "donut" of minimal change. Procession is an additional technique for reducing unwanted background signal.
- **Allow real time feedback from microscope to the model, aka "Digital Twin"**



SCAN ME

Link to poster, references, and more on GitHub!